Amendment to the claims:

Claims 1-4 (cancelled).

1	5. (currently amended) The circuit recited in claim 4 A circuit for determining
2	temperature of an active semiconductor device, comprising:
3	(A) a semiconductor substrate having thereon the active device;
4	(B) a bridge circuit comprising:
5	(i) a first thermal sensitive device disposed in thermal contact with an
, 6	electrode of the active device, such first thermal sensitive device having a pair of
7	terminals, a first one of the pair of terminals being connected to a first node and a
8	second one of the pair of terminals being connected to a second node:
9	(ii) a second thermal sensitive device disposed in thermal contact with the
10	electrode of the active device, such second thermal sensitive device having a pair
11	of terminals, a first one of the pair of terminals being connected to a third node
12	and a second one of the pair of terminals being connected to a fourth node;
13	(iii) a third thermal sensitive device disposed in thermal contact with the
14	substrate, such third thermal sensitive device having a pair of terminals, a first one
15	of the pair of terminals being connected to the second node and a second one of
16	the pair of terminals being connected to the fourth node;
17	(iv) a fourth thermal sensitive device disposed in thermal contact with the
18	substrate, such fourth thermal sensitive device having a pair of terminals, a first
19	one of the pair of terminals being connected to the first node and a second one of
20	the pair of terminals being connected to the third node;
21	(v) a voltage potential connected between the first node and the fourth
22	node:
23	(vi) an output provided by the second node and the third node;
24	including a tuning circuit coupled to an output electrode of the transistor, such tuning
25	circuit having a tunable element controlled by a control signal fed to such tunable
26	element.

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- 1 6. (original) The circuit recited in claim 5 including a processor responsive to a voltage
- 2 produced at the output of the bridge and a signal representative of power fed to the
- 3 transistor.
- 1 Claims 7-10 (cancelled).
- 1 11. (currently amended) The circuit recited in claim 10. A circuit for determining
- 2 <u>temperature of an active semiconductor device, comprising:</u>
- 3 (A) a semiconductor substrate having thereon the active device:
- 4 (B) a Wheatstone bridge circuit having in each of four branches thereof a thermal
- 5 <u>sensitive device, one pair of such thermal sensitive devices being in thermal</u>
- 6 contact with an electrode of the active device;
- 7 <u>wherein the thermal sensitive devices are resistors;</u>
- 8 wherein the active device is a transistor; and
- 9 -including a tuning circuit coupled to an output of the transistor, such tuning
- circuit having a tunable element controlled by a control signal fed to such tunable
- 11 element.
- 1 12. (original) The circuit recited in claim 11 including a processor responsive to a voltage
- 2 produced at an output of the Wheatstone bridge circuit and a signal representative of
- 3 power fed to the transistor.
- 1 13. (original) The circuit recited in claim 12 wherein the output provided by the
- Wheatstone bridge provides a measure of a temperature difference between the
- 3 temperature of the transistor and ambient temperature.

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1	14. (currently amended) The circuit recited in claim 13 wherein the processor produces
2	the control signal to maximize power fed to the transistor and minimize power
3	dissipated by such transistor.
1	Claims15 – 17 (cancelled).
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1	18. (currently amended) The circuit recited in claim 17A circuit for determining
2	temperature of an active semiconductor device, comprising:
3	(A) a semiconductor substrate having thereon the active device:
4	(B) a Wheatstone bridge circuit having in each of four branches thereof a thermal
5	sensitive device, one pair of such thermal sensitive devices being in thermal
6	contact with an electrode of the active device;
7	wherein another pair of such thermal sensitive devices is in thermal contact with
8	the substrate;
9	wherein the thermal sensitive devices are resistors;
10	wherein the active device is a transistor; and
11	including a tuning circuit coupled to an output of the transistor, such tuning
12	circuit having a tunable element controlled by a control signal fed to such tunable
13	element.
1	19. (original) The circuit recited in claim 18 including a processor responsive to a
2	voltage produced at an output of the Wheatstone bridge circuit and a signal
3	representative of power fed to the transistor.
1	20. (original) The circuit recited in claim 19 wherein the output provided by the
2	Wheatstone bridge provides a measure of a temperature difference between the

temperature of the transistor and ambient temperature.

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- 1 21. (original) The circuit recited in claim 20 wherein the processor produces the control signal to
- 2 maximize power fed to the transistor and minimize power dissipated by such transistor.